











**CSD18542KTT** 

SLPS590A - MARCH 2016-REVISED MARCH 2017

# CSD18542KTT 60-V N-Channel NexFET™ Power MOSFET

#### **Features**

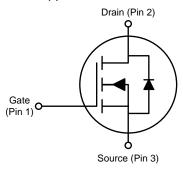
- Ultra-Low Q<sub>a</sub> and Q<sub>ad</sub>
- Low-Thermal Resistance
- Avalanche Rated
- Logic Level
- Lead-Free Terminal Plating
- **RoHS Compliant**
- Halogen Free
- D<sup>2</sup>PAK Plastic Package

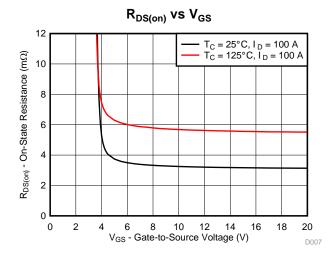
### **Applications**

- DC-DC Conversion
- Secondary Side Synchronous Rectifier
- Motor Control

### 3 Description

This 60-V, 3.3-m $\Omega$ , D<sup>2</sup>PAK (TO-263) NexFET<sup>TM</sup> power MOSFET is designed to minimize losses in power conversion applications.





#### **Product Summary**

$T_A = 25^\circ$	С	TYPICAL VA	UNIT		
$V_{DS}$	Drain-to-Source Voltage	60	V		
$Q_g$	Gate Charge Total (10 V)	44	nC		
$Q_{gd}$	Gate Charge Gate-to-Drain 6.9				
R <sub>DS(on)</sub>	Drain-to-Source On Resistance	V <sub>GS</sub> = 4.5 V 4.0		mΩ	
	Drain-to-Source On Resistance	V <sub>GS</sub> = 10 V 3.3		11177	
V <sub>GS(th)</sub>	Threshold Voltage	1.8	V		

### **Device Information**<sup>(1)</sup>

DEVICE	QTY	MEDIA	PACKAGE	SHIP
CSD18542KTT	500		D <sup>2</sup> PAK	Tape
CSD18542KTTT	50	13-Inch Reel	Plastic Package	and Reel

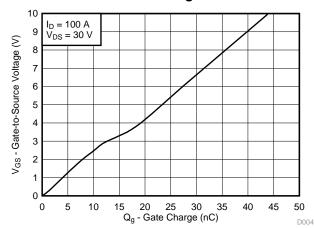
(1) For all available packages, see the orderable addendum at the end of the data sheet.

#### **Absolute Maximum Ratings**

T <sub>A</sub> = 2	5°C	VALUE	UNIT
V <sub>DS</sub>	Drain-to-Source Voltage	60	V
$V_{\text{GS}}$	Gate-to-Source Voltage	±20	٧
	Continuous Drain Current (Package Limited)	200	
I <sub>D</sub>	Continuous Drain Current (Silicon Limited), $T_C = 25^{\circ}C$	170	Α
	Continuous Drain Current (Silicon Limited), $T_C = 100$ °C	120	
$I_{DM}$	Pulsed Drain Current <sup>(1)</sup>	400	Α
$P_D$	Power Dissipation	250	W
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction, Storage Temperature	-55 to 175	ပ္
E <sub>AS</sub>	Avalanche Energy, Single Pulse $I_D$ = 75 A, L = 0.1 mH, $R_G$ = 25 $\Omega$	281	mJ

(1) Max  $R_{\theta JC}$  = 0.6°C/W, pulse duration ≤ 100  $\mu s$ , duty cycle ≤ 1%.

### **Gate Charge**





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# 4 Revision History

CI	Changes from Original (March 2016) to Revision A						
•	Changed the values for $C_{OSS}$ , $Q_{gs}$ , $t_r$ , $t_{d(off)}$ , $t_f$ , $Q_{rr}$ , and $t_{rr}$ in the <i>Electrical Characteristics</i> table						
•	Added Receiving Notification of Documentation Updates section to the Device and Documentation Support section	١					

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# 5 Specifications

### 5.1 Electrical Characteristics

 $T_A = 25^{\circ}C$  (unless otherwise stated)

PARAMETER	TEST CONDITIONS	MIN T	YP MAX	UNIT
CHARACTERISTICS				
Drain-to-source voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	60		V
Drain-to-source leakage current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 48 V		1	μА
Gate-to-source leakage current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V		100	nA
Gate-to-source threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.5	1.8 2.2	V
Drain to acureo an registence	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 100 A	4	4.0 5.1	<b>~0</b>
Drain-to-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 100 A	;	3.3 4.0	mΩ
Transconductance	V <sub>DS</sub> = 6 V, I <sub>D</sub> = 100 A	1	98	S
C CHARACTERISTICS				
Input capacitance		39	00 5070	pF
Output capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 30 \text{ V}, f = 1 \text{ MHz}$	5	70 740	pF
Reverse transfer capacitance			11 14	pF
Series gate resistance			1.3 2.6	Ω
Gate charge total (4.5 V)			21 27	nC
Gate charge total (10 V)			44 57	nC
Gate charge gate-to-drain	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 100 A	(	6.9	nC
Gate charge gate-to-source			10	nC
Gate charge at V <sub>th</sub>		-	7.3	nC
Output charge	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V		63	nC
Turnon delay time			6	ns
Rise time	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V},$		5	ns
Turnoff delay time	$I_{DS} = 100 \text{ A}, R_G = 0 \Omega$		18	ns
Fall time			21	ns
HARACTERISTICS				
Diode forward voltage	I <sub>SD</sub> = 100 A, V <sub>GS</sub> = 0 V	(	0.9 1.0	V
Reverse recovery charge	V <sub>DS</sub> = 30 V, I <sub>F</sub> = 100 A,	1	48	nC
Reverse recovery time	di/dt = 300 A/μs		53	ns
	Drain-to-source voltage Drain-to-source leakage current Gate-to-source leakage current Gate-to-source threshold voltage  Drain-to-source on resistance  Transconductance CCHARACTERISTICS Input capacitance Output capacitance Reverse transfer capacitance Series gate resistance Gate charge total (4.5 V) Gate charge gate-to-drain Gate charge gate-to-source Gate charge at V <sub>th</sub> Output charge Turnon delay time Rise time Turnoff delay time Fall time HARACTERISTICS Diode forward voltage Reverse recovery charge	PARAMETER         TEST CONDITIONS           CHARACTERISTICS         Drain-to-source voltage $V_{GS} = 0 \text{ V}$ , $I_D = 250 \text{ μA}$ Drain-to-source leakage current $V_{GS} = 0 \text{ V}$ , $V_{DS} = 48 \text{ V}$ Gate-to-source leakage current $V_{DS} = 0 \text{ V}$ , $V_{DS} = 250 \text{ μA}$ Drain-to-source on resistance $V_{DS} = V_{GS}$ , $I_D = 250 \text{ μA}$ Drain-to-source on resistance $V_{DS} = 4.5 \text{ V}$ , $I_D = 100 \text{ A}$ Transconductance $V_{DS} = 6 \text{ V}$ , $I_D = 100 \text{ A}$ CCHARACTERISTICS         Input capacitance           Input capacitance         Output capacitance           Series gate resistance         V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 30 V, $f = 1 \text{ MHz}$ Gate charge total (4.5 V)         Gate charge state to-drain           Gate charge gate-to-source         V <sub>DS</sub> = 30 V, I <sub>D</sub> = 100 A           Gate charge at V <sub>th</sub> V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V           Turnon delay time         V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 10 V, I <sub>DS</sub> = 100 A, R <sub>G</sub> = 0 Ω           Fall time         I <sub>DS</sub> = 100 A, V <sub>GS</sub> = 0 V           HARACTERISTICS         Diode forward voltage         I <sub>DS</sub> = 100 A, V <sub>GS</sub> = 0 V           Reverse recovery charge         V <sub>DS</sub> = 30 V, I <sub>T</sub> = 100 A, V <sub>T</sub> = 1	PARAMETER         TEST CONDITIONS         MIN         T           CHARACTERISTICS         Drain-to-source voltage $V_{GS} = 0 \text{ V}$ , $I_{D} = 250 \text{ μA}$ 60           Drain-to-source leakage current $V_{GS} = 0 \text{ V}$ , $V_{DS} = 48 \text{ V}$ 60           Gate-to-source leakage current $V_{DS} = 0 \text{ V}$ , $V_{DS} = 20 \text{ V}$ 1.5           Gate-to-source threshold voltage $V_{DS} = 0 \text{ V}$ , $V_{DS} = 20 \text{ V}$ 1.5           Drain-to-source on resistance $V_{CS} = 4.5 \text{ V}$ , $I_{D} = 100 \text{ A}$ 4           Transconductance $V_{CS} = 10 \text{ V}$ , $I_{D} = 100 \text{ A}$ 1           Transconductance $V_{DS} = 6 \text{ V}$ , $I_{D} = 100 \text{ A}$ 1           CCHARACTERISTICS         Input capacitance         39           Output capacitance $V_{CS} = 0 \text{ V}$ , $V_{DS} = 30 \text{ V}$ , $f = 1 \text{ MHz}$ 5           Reverse transfer capacitance $V_{CS} = 0 \text{ V}$ , $V_{DS} = 30 \text{ V}$ , $V$	Characteristrics   V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA   60

### 5.2 Thermal Information

 $T_A = 25$ °C (unless otherwise stated)

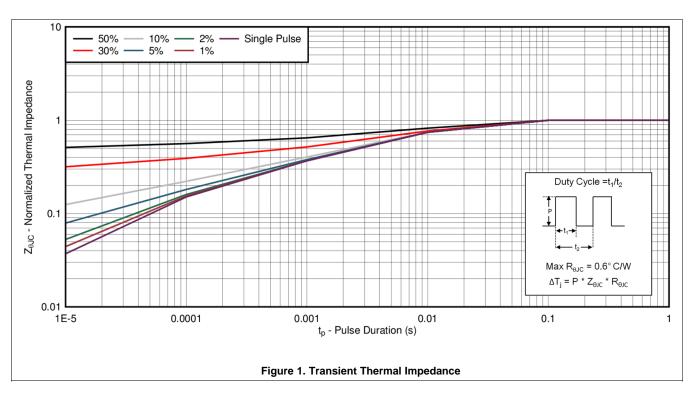
	THERMAL METRIC	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-case thermal resistance			0.6	°C/W
$R_{\theta JA}$	Junction-to-ambient thermal resistance			62	°C/W

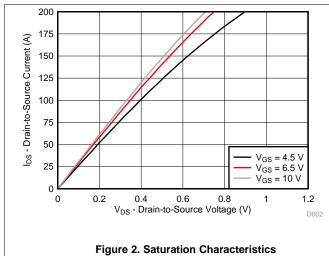
Product Folder Links: CSD18542KTT

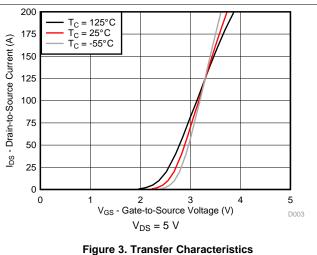


## 5.3 Typical MOSFET Characteristics

 $T_A = 25$ °C (unless otherwise stated)





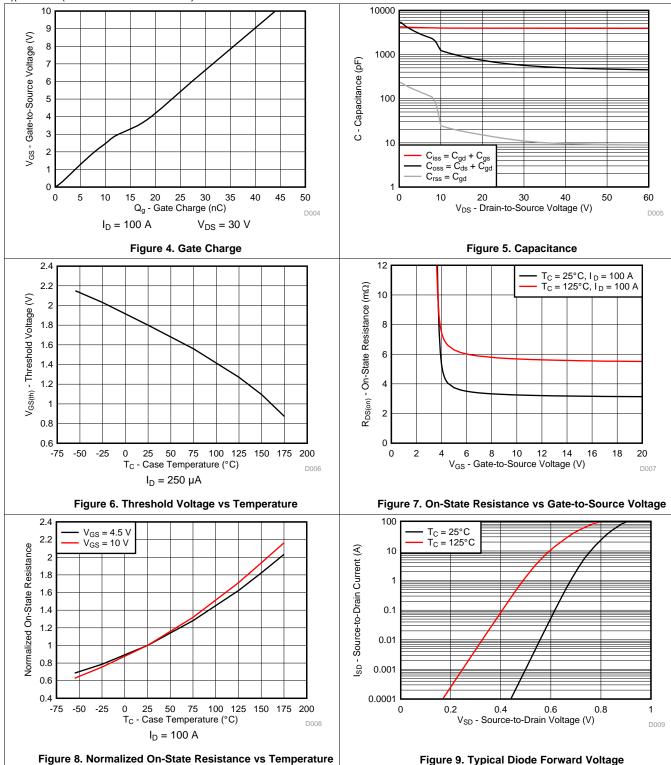


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### **Typical MOSFET Characteristics (continued)**

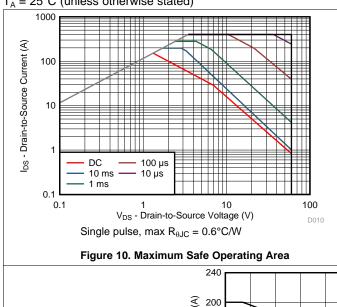
 $T_A = 25$ °C (unless otherwise stated)





### **Typical MOSFET Characteristics (continued)**

 $T_A = 25$ °C (unless otherwise stated)



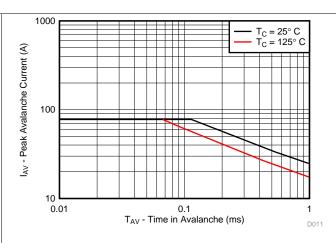


Figure 11. Single Pulse Unclamped Inductive Switching

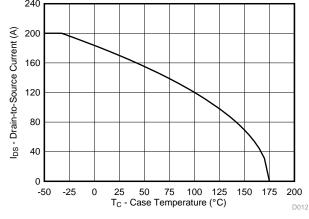


Figure 12. Maximum Drain Current vs Temperature

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## Device and Documentation Support

#### 6.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on Alert me to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 6.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community T's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support TI's Design Support Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 6.3 Trademarks

NexFET, E2E are trademarks of Texas Instruments. All other trademarks are the property of their respective owners.

#### Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### 6.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

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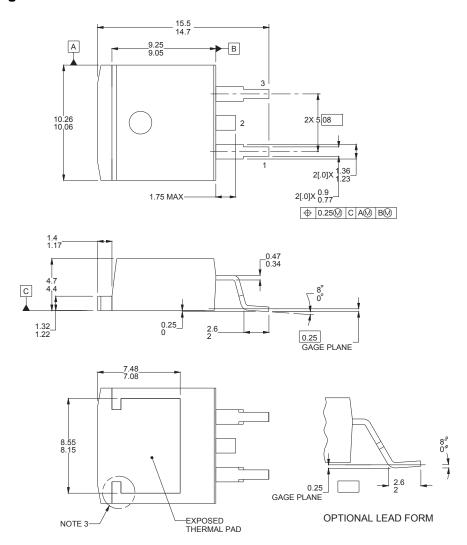
Product Folder Links: CSD18542KTT



### 7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

### 7.1 KTT Package Dimensions



### Notes:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. Features may not exist and shape may vary per different assembly sites.

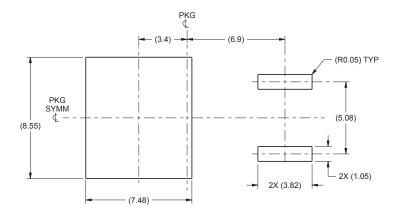
**Table 1. Pin Configuration** 

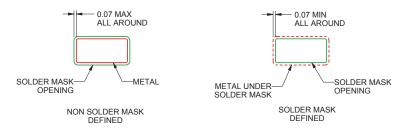
POSITION	DESIGNATION
Pin 1	Gate
Pin 2 / Tab	Drain
Pin 3	Source

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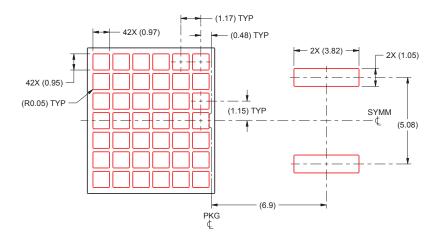
#### 7.2 Recommended PCB Pattern





For recommended circuit layout for PCB designs, see *Reducing Ringing Through PCB Layout Techniques* (SLPA005).

### 7.3 Recommended Stencil Opening (0.125 mm Stencil Thickness)



#### Notes:

- 1. This package is designed to be soldered to a thermal pad on the board. See application notes *PowerPAD Thermally Enhanced Package* (SLMA002) and *PowerPAD Made Easy* (SLMA004) for more information.
- 2. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 3. Board assembly site may have different recommendations for stencil design.

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## **PACKAGE OPTION ADDENDUM**

10-Dec-2020

#### PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CSD18542KTT	ACTIVE	DDPAK/ TO-263	KTT	3	500	RoHS-Exempt & Green	SN	Level-2-260C-1 YEAR	-55 to 175	CSD18542KTT	Samples
CSD18542KTTT	ACTIVE	DDPAK/ TO-263	KTT	3	50	RoHS-Exempt & Green	SN	Level-2-260C-1 YEAR	-55 to 175	CSD18542KTT	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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